

4N32/ 4N33

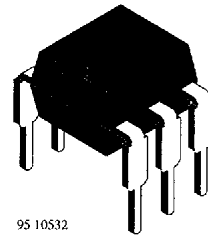
TEMIC
Semiconductors

Optocoupler with Photodarlington Output

Description

The 4N32 and 4N33 consist of a photodarlington optically coupled to a gallium arsenide infrared emitting diode in a 6 lead plastic dual inline package.

The elements are mounted on one leadframe using a coplanar technique, providing a fixed distance between input and output for highest safety requirements.



Applications

Galvanically separated circuits, non-interacting switches



Features

- High isolation resistance
- High Current Transfer Ratio
- Low coupling capacity typical 0.3 pF
- Low temperature coefficient of CTR
- UL recognized; file No. E 76222

Order Schematic

| Part Numbers | CTR-Ranking |
|--------------------------|-------------|
| 4N32/ 4N32S/ 4N33/ 4N33S | > 500% |

Suffix: S = Waterproofed device

Remarks

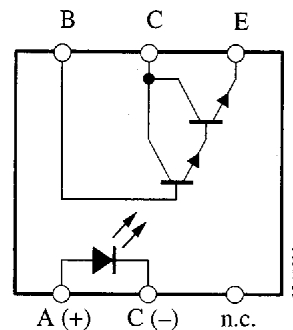
A waterproof construction is recommended for couplers where a pure water cleaning process is used instead of a standard-soldering/ cleaning process. In this case please order the part numbers with the suffix "S".

The waterproof construction corresponds with the coupling system "S", and does not belong to the part number itself.

Standard parts are marked with the letter "A".

This coupling system indicator "A" or "S" is in a separate (second) line of the marking.

Pin Connections



Absolute Maximum Ratings

Input (Emitter)

| Parameters | Test Conditions | Symbol | Value | Unit |
|-----------------------|---------------------------|-----------|-------|------------|
| Reverse voltage | | V_R | 5 | V |
| Forward current | | I_F | 80 | mA |
| Forward surge current | $t_p \leq 10 \mu s$ | I_{FSM} | 3 | A |
| Power dissipation | $T_{amb} \leq 25^\circ C$ | P_V | 100 | mW |
| Junction temperature | | T_j | 125 | $^\circ C$ |

Output (Detector)

| Parameters | Test Conditions | Symbol | Value | Unit |
|---------------------------|-------------------------------|-----------|-------|------------|
| Collector base voltage | | V_{CBO} | 50 | V |
| Collector emitter voltage | | V_{CEO} | 30 | V |
| Emitter collector voltage | | V_{ECO} | 5 | V |
| Collector current | | I_C | 150 | mA |
| Peak collector current | $t_p/T = 0.5, t_p \leq 10 ms$ | I_{CM} | 200 | mA |
| Power dissipation | $T_{amb} \leq 25^\circ C$ | P_V | 150 | mW |
| Junction temperature | | T_j | 125 | $^\circ C$ |

Coupler

| Parameters | Test Conditions | Symbol | Value | Unit |
|------------------------------|-------------------------------|---------------|-------------|------------|
| Isolation test voltage (RMS) | | $V_{IO}^{1)}$ | 3.75 | kV |
| Total power dissipation | $T_{amb} \leq 25^\circ C$ | P_{tot} | 250 | mW |
| Ambient temperature range | | T_{amb} | -55 to +100 | $^\circ C$ |
| Storage temperature range | | T_{stg} | -55 to +125 | $^\circ C$ |
| Soldering temperature | 2 mm from case, $t \leq 10 s$ | T_{sd} | 260 | $^\circ C$ |

¹⁾ Related to standard climate 23/50 DIN 50014

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Electrical Characteristics

$T_{amb} = 25^{\circ}\text{C}$

Input (Emitter)

| Parameters | Test Conditions | Symbol | Min. | Typ. | Max. | Unit |
|----------------------|---------------------------------|------------|------|------|------|------|
| Forward voltage | $I_F = 50 \text{ mA}$ | V_F | | 1.25 | 1.5 | V |
| Breakdown voltage | $I_R = 100 \text{ }\mu\text{A}$ | $V_{(BR)}$ | 5 | | | mW |
| Junction capacitance | $V_R = 0, f = 1 \text{ MHz}$ | C_j | | 50 | | pF |

Output (Detector)

| Parameters | Test Conditions | Symbol | Min. | Typ. | Max. | Unit |
|-------------------------------------|---|---------------|------|------|------|------|
| Collector base breakdown voltage | $I_C = 100 \text{ }\mu\text{A}$ | $V_{(BR)CBO}$ | 50 | | | V |
| Collector emitter breakdown voltage | $I_C = 1 \text{ mA}$ | $V_{(BR)CEO}$ | 30 | | | V |
| Emitter collector breakdown voltage | $I_C = 100 \text{ }\mu\text{A}$ | $V_{(BR)ECO}$ | 5 | | | V |
| Collector dark current | $V_{CE} = 10 \text{ V}, I_F = 0, E = 0$ | I_{CEO} | | | 100 | nA |

Coupler

| Parameters | Test Conditions | Symbol | Min. | Typ. | Max. | Unit |
|--------------------------------------|--|---------------|------|-----------|------|----------|
| Isolation test voltage (RMS) | $f = 50 \text{ Hz}, t = 2 \text{ s}$ | $V_{IO}^{1)}$ | 3.75 | | | kV |
| Isolation resistance | $V_{IO} = 1000 \text{ V},$ 40% relative humidity | $R_{IO}^{1)}$ | | 10^{12} | | Ω |
| I_C/I_F | $I_F = 10 \text{ mA},$ $V_{CE} = 10 \text{ V},$ $t_p/T = 0.01, t_p = 0.3 \text{ ms}$ | CTR | 5 | | | |
| Collector emitter saturation voltage | $I_F = 8 \text{ mA}, I_C = 2 \text{ mA}$ | V_{CEsat} | | | 1 | V |
| Cut-off frequency | $I_F = 2 \text{ mA}, V_{CE} = 10 \text{ V},$ $R_L = 100 \text{ }\Omega$ | f_c | | 30 | | kHz |
| Coupling capacitance | $f = 1 \text{ MHz}$ | C_k | | 0.3 | | pF |

1) Related to standard climate 23/50 DIN 50014

Switching Characteristics

$V_S = 10\text{ V}$

| Type | $R_L = 100\ \Omega$ (see figure 1) | | | | | | $R_L = 1\text{ k}\Omega$ | | | |
|-------------|------------------------------------|--------------------|-----------------------|--------------------|--------------------|------------------------|--------------------------|-----------------------|------------------------|------------------|
| | $t_d[\mu\text{s}]$ | $t_r[\mu\text{s}]$ | $t_{on}[\mu\text{s}]$ | $t_s[\mu\text{s}]$ | $t_f[\mu\text{s}]$ | $t_{off}[\mu\text{s}]$ | $I_C[\text{mA}]$ | $t_{on}[\mu\text{s}]$ | $t_{off}[\mu\text{s}]$ | $I_F[\text{mA}]$ |
| 4N32/ 4N32S | | | 50 | | | 40 | 50 | | | |
| 4N33/ 4N33S | | | 50 | | | 40 | 50 | | | |

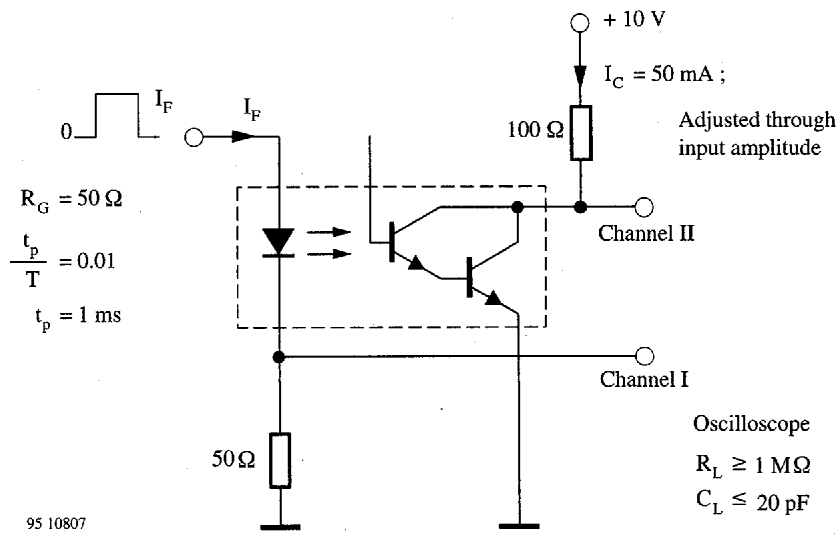


Figure 1. Test circuit

Typical Characteristics ($T_{amb} = 25^{\circ}\text{C}$, unless otherwise specified)

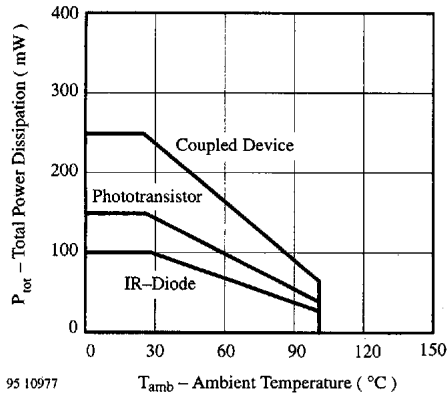


Figure 2. Total Power Dissipation vs. Ambient Temperature

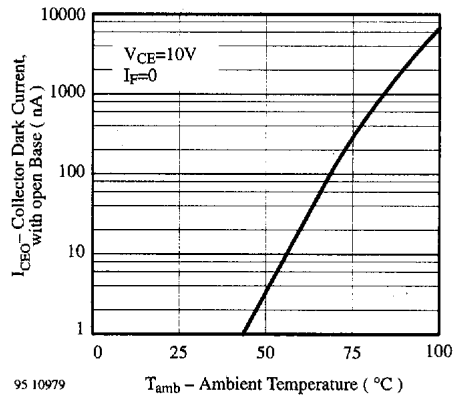


Figure 5. Collector Dark Current vs. Ambient Temperature

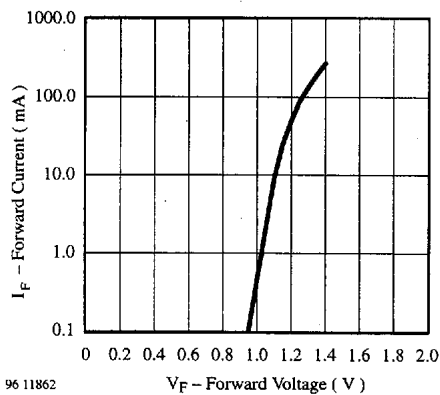


Figure 3. Forward Current vs. Forward Voltage

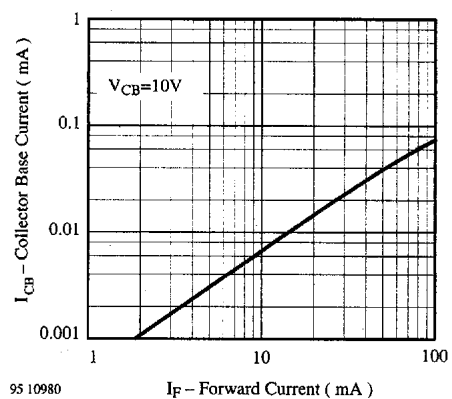


Figure 6. Collector Base Current vs. Forward Current

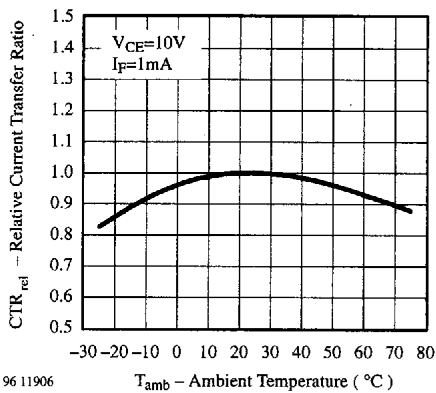


Figure 4. Rel. Current Transfer Ratio vs. Ambient Temperature

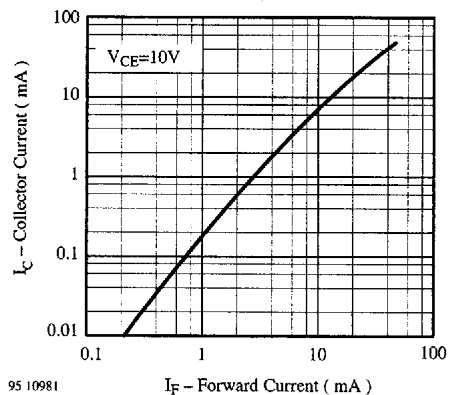


Figure 7. Collector Current vs. Forward Current

Typical Characteristics ($T_{amb} = 25^{\circ}C$, unless otherwise specified)

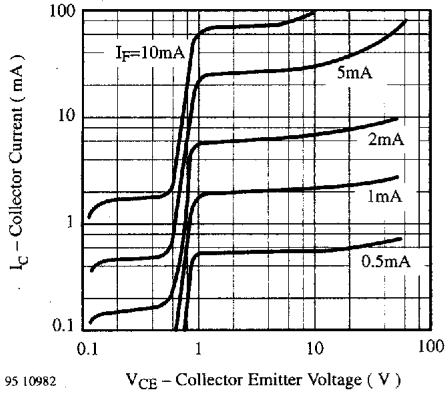


Figure 8. Collector Current vs. Collector Emitter Voltage

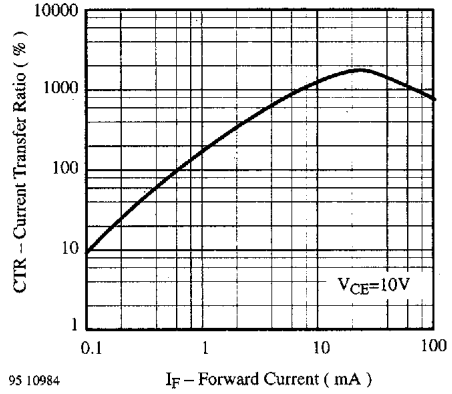


Figure 10. Current Transfer Ratio vs. Forward Current

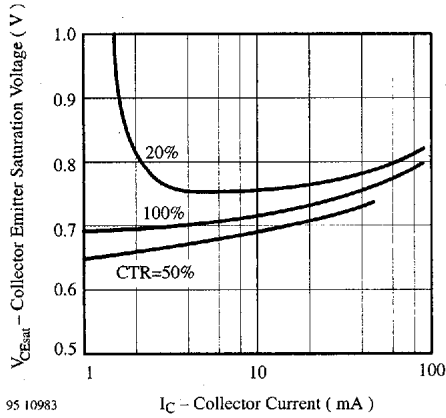
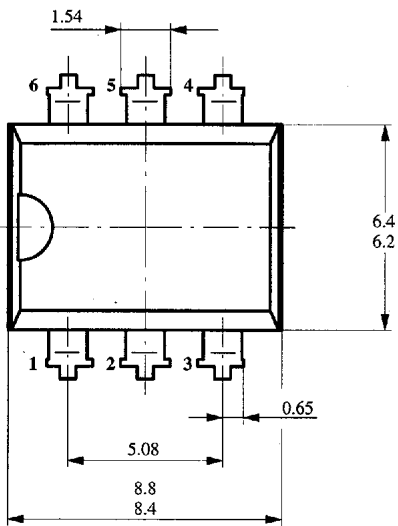
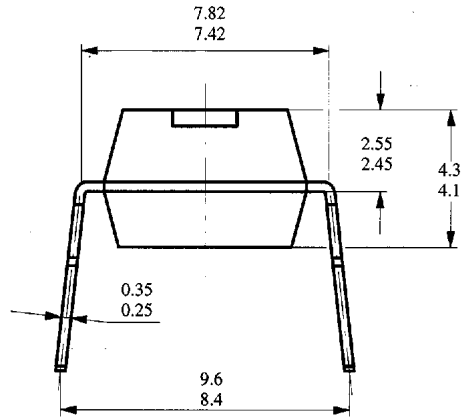
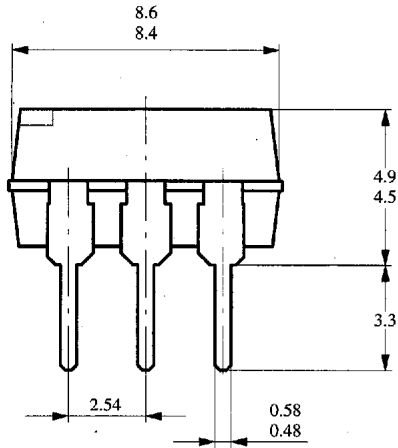


Figure 9. Collector Emitter Sat. Voltage vs. Collector Current

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Dimensions in mm




technical drawings
according to DIN
specifications

95 10931